

MOS FIELD EFFECT TRANSISTOR μ PA1816

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1816 is a switching device which can be driven directly by a 1.8 V power source.

This device features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power management of notebook computers and so on.

FEATURES

- 1.8 V drive available
- · Low on-state resistance

RDS(on)1 = 15 m Ω MAX. (VGS = -4.5 V, ID = -4.5 A)

 $R_{DS(on)2} = 16 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.0 \text{ V, Ip} = -4.5 \text{ A)}$

 $R_{DS(on)3} = 22.5 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -2.5 \text{ V, ID} = -4.5 \text{ A)}$

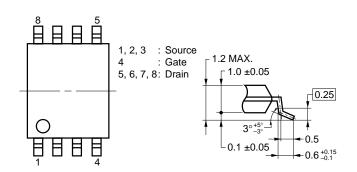
RDS(on)4 = 41.5 m Ω MAX. (VGS = -1.8 V, ID = -2.5 A)

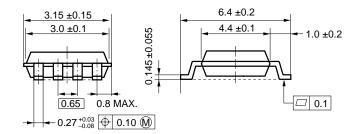
Built-in G-S protection diode against ESD

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1816GR-9JG	Power TSSOP8

PACKAGE DRAWING (Unit: mm)

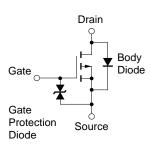




ABSOLUTE MAXIMUM RATINGS ($T_A = 25$ °C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	-12	V
Gate to Source Voltage (Vps = 0 V)	Vgss	∓ 8.0	V
Drain Current (DC) (T _A = 25°C)	ID(DC)	∓ 9.0	Α
Drain Current (pulse) Note1	ID(pulse)	∓ 36	Α
Total Power Dissipation Note2	Рт	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on ceramic substrate of 5000 mm² x 1.1 mm

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

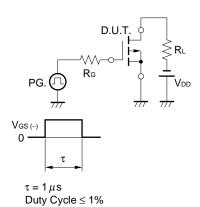
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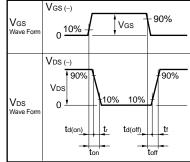


ELECTRICAL CHARACTERISTICS (TA = 25°C)

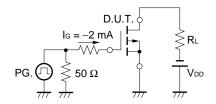
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = −12 V, V _{GS} = 0 V			-1.0	μΑ
Gate Leakage Current	Igss	Vgs = ∓ 8.0 V, Vps = 0 V			∓ 10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, I_{D} = -1.0 \text{ mA}$	-0.45	-0.75	-1.5	V
Forward Transfer Admittance	yfs	V _{DS} = -10 V, I _D = -4.5 A	11	22		S
Drain to Source On-state Resistance	RDS(on)1	V _{GS} = -4.5 V, I _D = -4.5 A		12.0	15	mΩ
	RDS(on)2	V _{GS} = -4.0 V, I _D = -4.5 A		12.5	16	mΩ
	RDS(on)3	V _{GS} = -2.5 V, I _D = -4.5 A		16.2	22.5	mΩ
	RDS(on)4	V _{GS} = -1.8 V, I _D = -2.5 A		23.7	41.5	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V		1570		pF
Output Capacitance	Coss	V _G S = 0 V		400		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		240		pF
Turn-on Delay Time	t d(on)	$V_{DD} = -10 \text{ V}, I_{D} = -4.5 \text{ A}$		16		ns
Rise Time	tr	V _{GS} = -4.0 V		132		ns
Turn-off Delay Time	t d(off)	R _G = 10 Ω		223		ns
Fall Time	t _f			295		ns
Total Gate Charge	Q _G	V _{DD} = -10 V		15		nC
Gate to Source Charge	Qgs	V _{GS} = -4.0 V		3.0		nC
Gate to Drain Charge	Q _{GD}	I _D = -9.0 A		4.5		nC
Body Diode Forward Voltage	V _F (S-D)	IF = 9.0 A, VGS = 0 V		0.82		V
Reverse Recovery Time	trr	IF = 9.0 A, Vgs = 0 V		490		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ μs		580		nC

TEST CIRCUIT 1 SWITCHING TIME

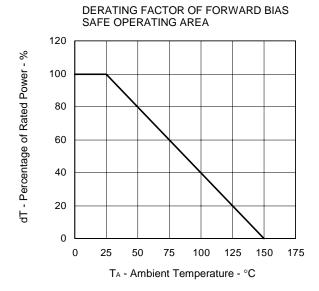




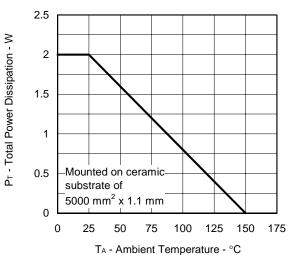
TEST CIRCUIT 2 GATE CHARGE



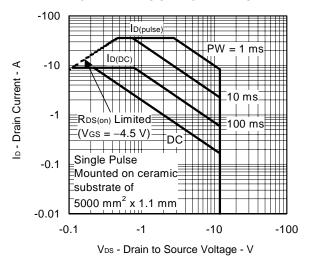
TYPICAL CHARACTERISTICS (TA = 25°C)



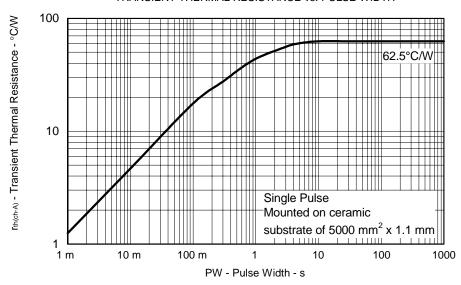
TOTAL POWER DISSIPATION vs. AMBIENT TEMPERATURE



FORWARD BIAS SAFE OPERATING AREA

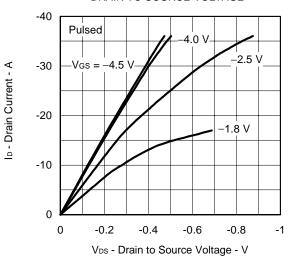


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

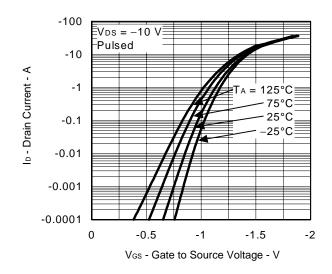


Data Sheet G16252EJ1V0DS

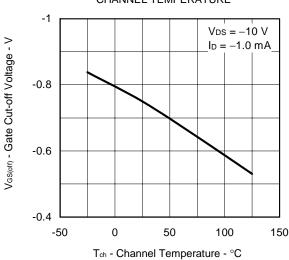
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



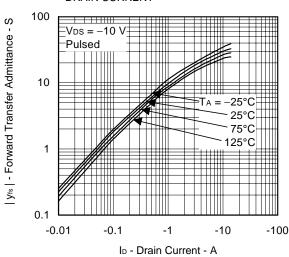
FORWARD TRANSFER CHARACTERISTICS



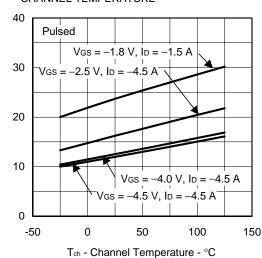
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



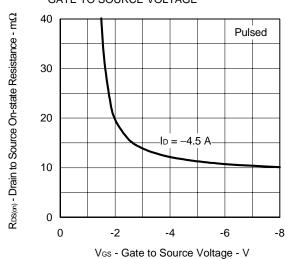
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



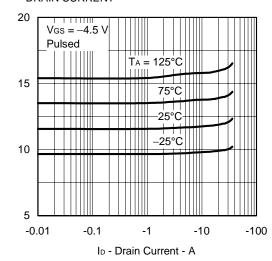
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



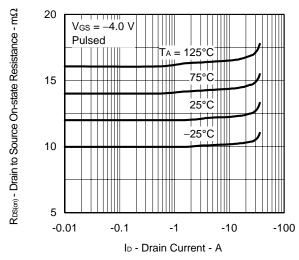
RDS(m) - Drain to Source On-state Resistance - m\Omega

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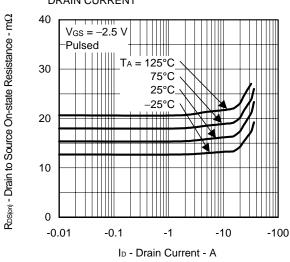
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



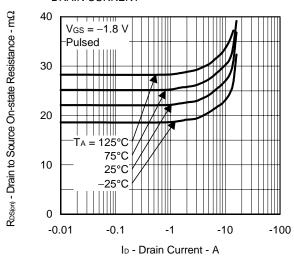
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



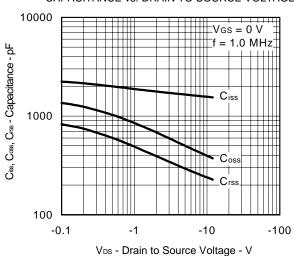
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



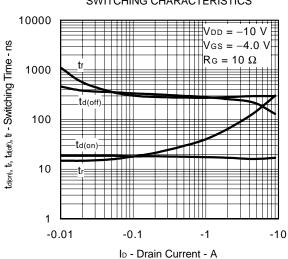
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



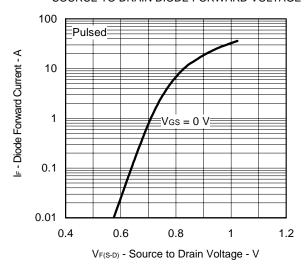
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



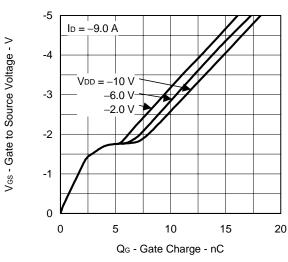
SWITCHING CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE



DYNAMIC INPUT/OUTPUT CHARACTERISTICS



NEC μ PA1816

[MEMO]

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